PATENT GOY 1741



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Rongjia Tao et al. : Art Unit: 1741

Serial No.: 10/007,575 : Examiner:

Filed: November 9, 2001

FOR: METHOD AND APPARATUS FOR

INCREASING AND MODULATING
THE YIELD SHEAR STRESS OF

ELECTRORHEOLOGICAL FLUIDS :

CROWN TO THE STATE OF THE STATE

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Assistant Commissioner for Patents Washington, D.C. 20231

SIR:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98 and to the duty of disclosure set forth in 37 C.F.R. § 1.56, the Examiner in charge of the above-identified application is requested to consider and make of record the references listed on the PTO 1449 (R&P) submitted herewith. Copies of each of the listed references are also enclosed.

Although the information submitted herewith may be "material" to the Examiner's consideration of the subject application, this submission is not intended to constitute an admission that such information is "prior art" as to the claimed invention.

In accordance with 37 C.F.R. § 1.97(g), the filing of this Information Disclosure Statement shall not be construed to mean that a search has been made.

No first Official Action has yet been received and it is presumed that none has yet been mailed. No fee is required. 37 C.F.R. § 1.97(b). Furthermore, all of the references disclosed herein were first cited in a communication from a foreign patent office in a counterpart foreign application within the last three months. Accordingly, a certification, as specified in 37 C.F.R. § 1.97(c), is provided herewith. Therefore, no fee is required, even if an Official Action has been mailed.

CERTIFICATION

The undersigned, an attorney registered to practice before the U.S. Patent and Trademark Office, hereby certifies that each reference disclosed in the subject Information Disclosure Statement was first cited in a communication from a foreign patent office in a counterpart foreign application not more than three months before the filing of the Information Disclosure Statement.

Respectfully submitted,

Robert L. Andersen, Reg. No. 25,771

Attorney for Applicants

RLA/pb

Enclosures: PTO Form 1449;

Copies of (3) References; International Search Report

Dated: March 7, 2003

Suite 301 One Westlakes, Berwyn P.O. Box 980 Valley Forge, PA 19482-0980 (610) 407-0700

The Assistant Commissioner for Patents is hereby authorized to charge payment to Deposit Account No. 18-0350 of any fees associated with this communication.

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231 on:

Patricia C. Boccella

FORM PTO-1449

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